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	AB	5,045,	,847	9/91	Tarui et al.				Ī.	T	Τ			
	AC	5,045,	,345	9/91	Singer				Γ	T	\top			
	AD	4,996,	,081	2/91	Ellul et al.					T	\top			
	AE	3,884,	,698	5/75	Kakihama et	t al.	_		一	<u> </u>	$\dagger \dagger$			
	AF	5,518,	,946	5/96	Kuroda		_		\vdash	\top	$\dagger \dagger$			
	AG	5,489,	7,542	2/96	(wai et al.				\vdash	\vdash	$\dagger \dagger$.	
	AH	4,330,	y,569	5/82	Gulett et al.					\vdash	H		<u>. </u>	
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		AB	5,587	7,344	12/96	Ishikawa					1			
		AC	4,439	2,270	3/84	Powell et al.					T			
		AD	5,773	3,325	6/98	Teramoto								
		AE	5,904	1,523	5/99	Feldman et	al.							
	_	AF	5,891	1,793	4/99	Gardner et a	J.							
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	AB	4,446,	,194	5/84	Candelaria							
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	AD	4,543,	,707	10/85	Ito et al.					T		
	AĒ	5,098,	,865	3/92	Machado et al.	 -		T		T		
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	AG	5,306,	,946	4/94	Yamamoto	· ·				T		
	AH	5,442,	,223	8/95	Fujii							
	Al	5,523,	,616	6/96	Den							
	AJ	5,756,	,404	5/98	Friedenreich et al.							
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maw	AS		Passivation of GaA- 1988; pp. 1412-141		CVD Silicon Nitride Films of Different	Stress States; IEEE Tra	insaction	ıs on	Electr	on Devic	es; Vol. 35, N	o. 9; Sept.
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MEN	AA	4,695,872	9/87	Chatterjee								
	AB	5,178,016	1/93	Dauenhauer et al.								
	AC	5,985,771	11/99	Moore et al.				\perp				
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		9/89	Hayashi									
	AF	5,304,829	4/94	Mori et al.	ori et al.							
	AG	5,925,494	7/99	Horn .		П						
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	AI	4,732,858	3/88	Brewer et al.		П		T				
	ĄJ	6,300,253	10/01	Moore, John T.								
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